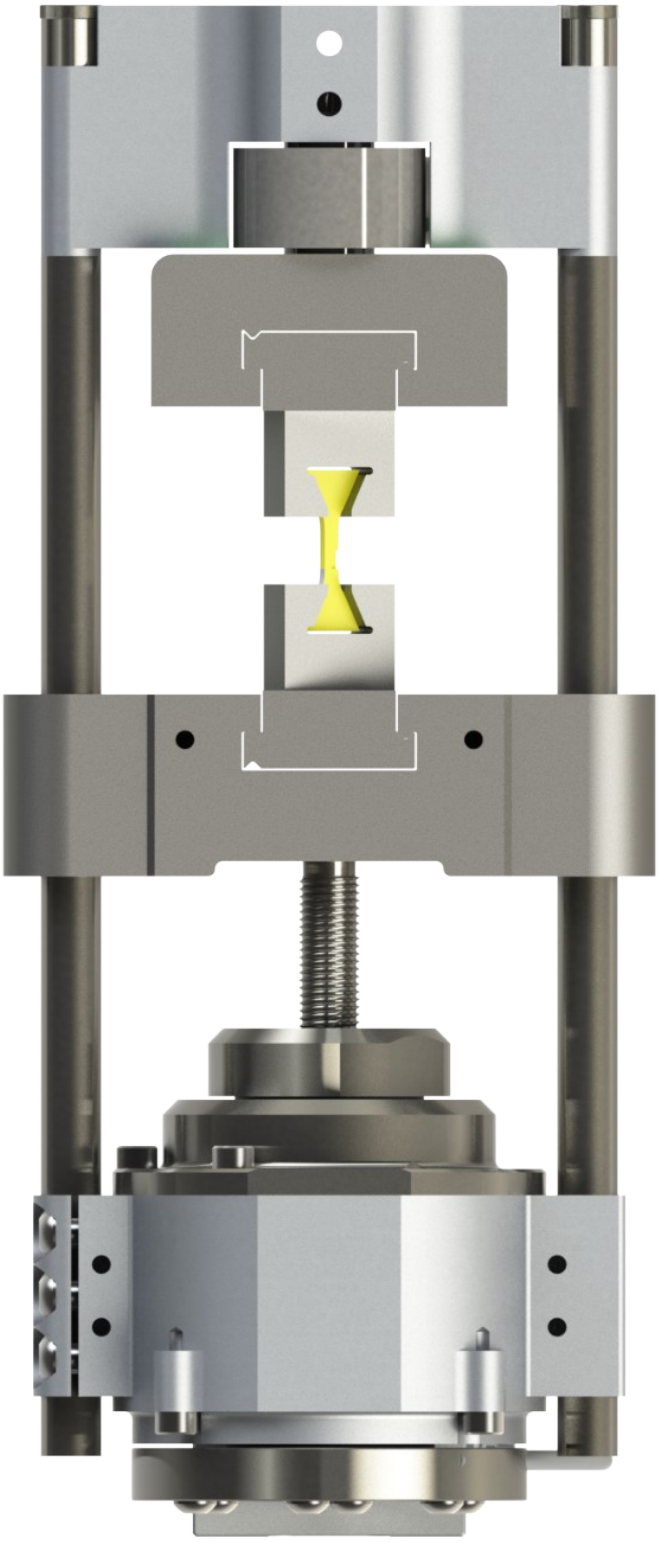
psylotech

µTS type-c

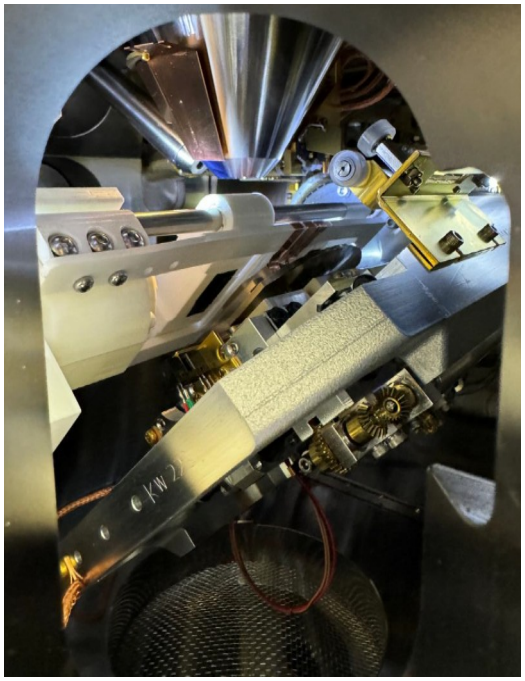
Compact Universal Test System for SEM, EBSD and tight spaces

Psylotech's µTS *type-c* is an ultra-compact universal load frame compatible with ultra-high vacuum scanning electron microscope (SEM) environments. The unique design minimizes out-of-plane motion, limiting false Digital Image Correlation strain measurements in an SEM, where 2D DIC is the only option. Grips are available for tension, compression, beam bending, etc.



SEM Compatibility

A 3D printed solid model ensures clearance within any brand of SEM and validates custom mounting plate designs before final installation. Psylotech provides the mounting plate according to user needs.



*actual size

info@psylotech.com
1.847.328.7100
Evanston, IL USA

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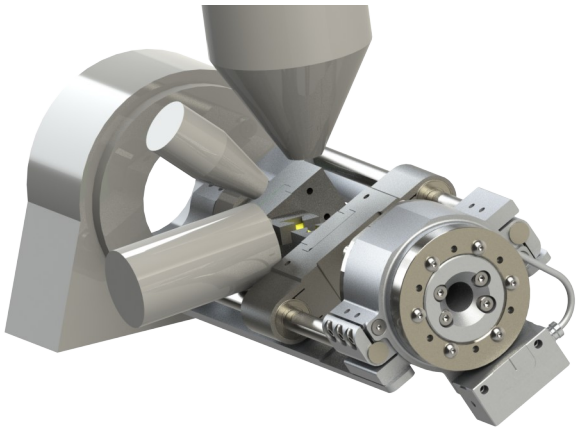


EBSD

The low system weight is compatible with SEM rotation stages, enabling the frame to readily be moved into position. The compact design minimizes the structure around the load train, leaving ample clearance around the sample for the electron backscatter detector. Special rotated and offset, shoulder mount grips place the sample surface close to the detector.

Speed & Fatigue

The direct-drive roller screw actuator enables low cycle fatigue testing.

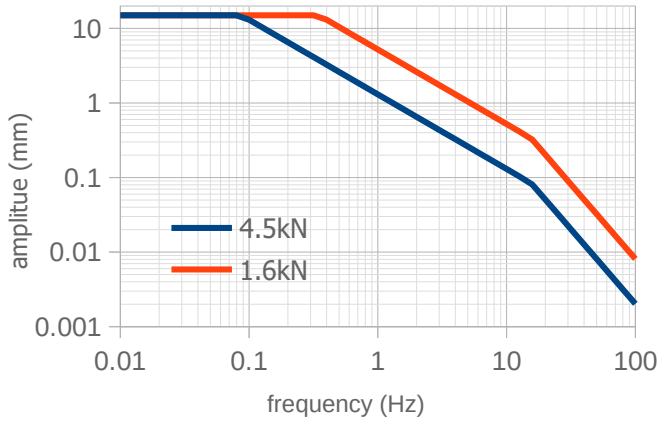
Psylotest3 Control Software

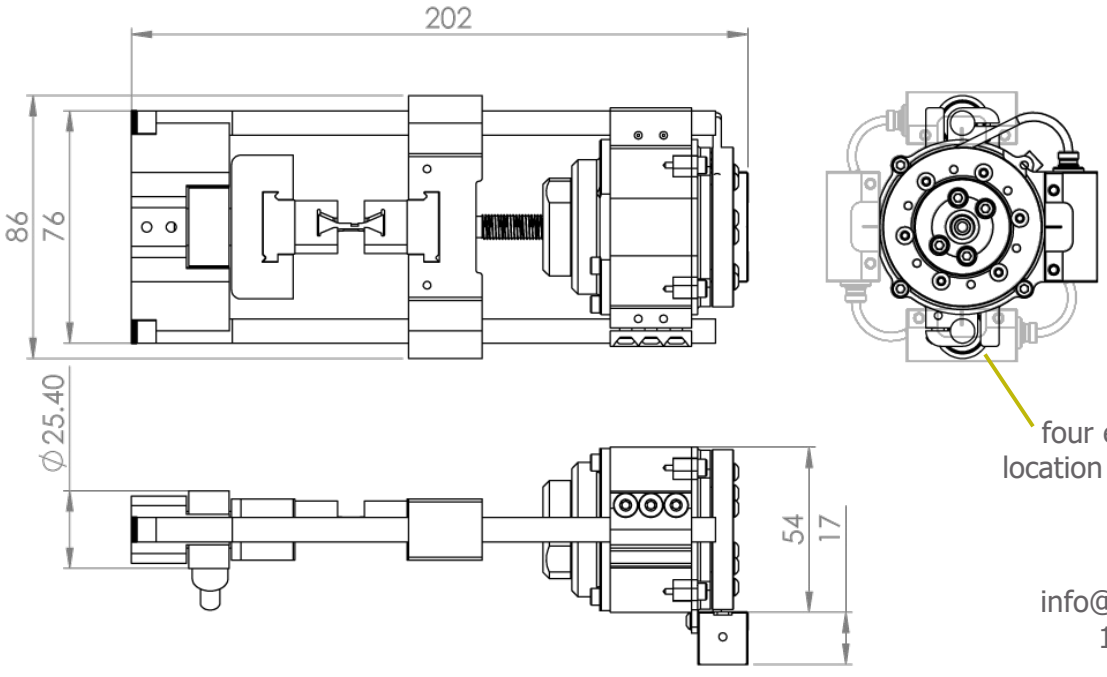
Custom image capture and stage centering modules can be integrated into Psylotest3, Psylotech's advanced motion control software. These modules are typically written in Python, utilizing a TCP/IP interface. Other test protocols are also readily available. Psylotest3 can also be modified to control temperature for laser or resistive heating applications.

Specifications

max. force capacity	4.5 kN
system weight	1.5 kg
stroke	25 mm
max. speed**	8 mm/s
axial backlash	20 µm
displacement resolution	<1 nm

*specifications subject to change without notice
**higher speeds available with reduced force capacity





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